

Response Under 37 CFR §1.116  
Expedited Procedure  
500.45763X00

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: S. KASUKABE et al

Application No.: 10/562,797

Filed: 12/29/2005

Title: PROBE CARD AND SEMICONDUCTOR TESTING DEVICE  
USING PROBE SHEET OR PROBE CARD AND  
SEMICONDUCTOR DEVICE PRODUCING METHOD

Art Unit: 2829 Exr.: R. ISLA RODAS CONF. No.: 8707

**AMENDMENT AFTER FINAL REJECTION UNDER 37 CFR §1.116**

**MS: AMENDMENT AFTER FINAL**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**April 7, 2008**

Sir:

In response to the Final Office Action dated December 7, 2007, the period of response for which extension is requested by the attached Petition for Extension of Time, please amend the above-identified application as listed below and as set forth on the following pages:

**Amendments to the Claims;**

**Remarks are included following the amendments.**

OK TO ENTER: /RI/

04/23/2008